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6	P E FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON.098CDV2	APPLICATION NO. 10/615,524	
	1 200 NEERMATION	DISCLOSURE STATEMENT			
1 '	اق رق/ ^ا	AFFLICANI	APPLICANT Basceri et al.		
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
9NB	1	6,339,527	01/2002	Farooq et al.	36/	ż	×
91/3	2	6,277,436	08/2001	Stauf et al.	427	126-3	
91/8	3	5,822,175	10/1998	Azuma, Masamichi	361	321.5	
9/6	4	5,581,436	12/1996	Summerfelt et al.	361	321-\$	7
W	5	5,185,689	02/1993	Maniar, Papu D.	361	7/3	
919	6	6,660,535	12/2003	Basceri et al.	438	3	X
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	FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. MICRON 098CDV2	APPLICATION NO. Unknown.
-	INFORMATION DISCLOSURE STATEMENT		18/619521
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W15	1	5,335,138	8/2/94	Sandhu et al.	361	383	+
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MB	3	5,506,166	4/9/96	Sandhu et al	438	396	
WB	4	5,717,234	2/10/98	Si et al.	257	295	7
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WB.	7.	5,889,299	3/30/99	Abe et al.	257	295	· V
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208	9	6,010,931	1/4/00	Sun et al.	438	240	
WB	10	6,117,482	9/12/00	Kawahara et al.	427	10	
9/13	11	6,136,639	10/24/00	Seon	438	239	
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WB	13	Hiromi Itoh et al., "Integration of BST Thin Film for Dram Fabrication,"
9/18		C. Basceri, "An Important Failure Mechanism in MOCVD (Ba Sr) TiO Thin Films: Resistance Degradation," Ferroelectric Thin Films IV, Materials Research Society, 1998, pp. 9-14
WB.	15	Chung Ming Chu and Pan Lin, "Electrical Properties and Crystal Structure of a (Ba Sr) TiO3 Films Prepared at Low Temperatures on a LaNiO3 Electrode by Radio-Frequency Magnetron Sputtering," Appl. Phys. Lett., Vol. 70 (2), 13 January 1997, pp. 249-51
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	1.	6,285,051	09/04/01	Ueda	et al.	257	296		
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